

10/500427

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PATENT

HEIWA.014AUS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant	:	Shuuske Kantake)	Group Art Unit
)	
Serial No.	:	New U.S. National Stage)	
		Application)	
)	
Filed	:	International Filing Date)	
		January 9, 2003)	
)	
For	:	TEST EQUIPMENT FOR LSI AS)	
		A DEVICE UNDER TEST,)	
		JITTER ANALYZER, AND PHASE)	
		DIFFERENCE DETECTOR)	
)	
Examiner	:	Unknown)	

PRELIMINARY AMENDMENT

Hon. Commissioner
of Patents and Trademarks
Alexandria, VA 22313-1450

Dear Sir:

This amendment is submitted for the above-identified patent application for correcting the forms of the claims in the national stage of the International Application. Please make the following changes.